

## I/CV (I-V, C-V Characterization) Automation Software

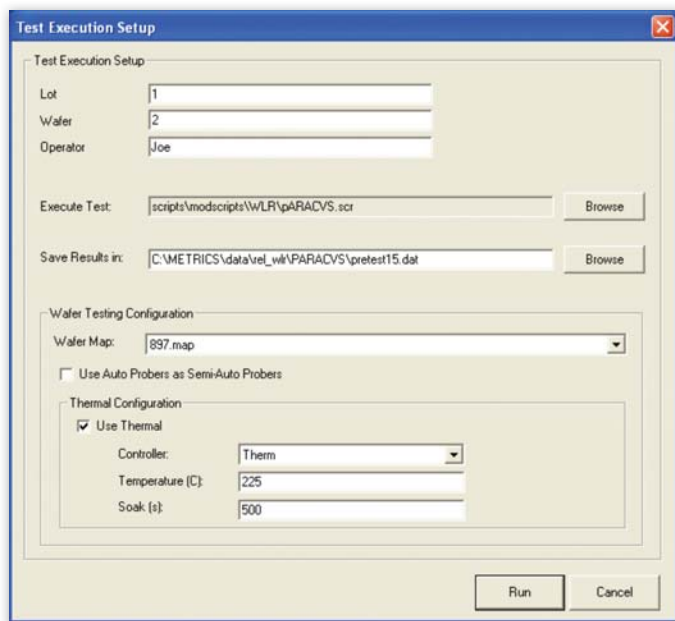
*Point. Click. Measure. It's as simple as that.*

Metrics™ I/CV provides a Windows XP Professional “wizard-based” operator test environment, test execution and sequencing, along with data logging and post-analysis. Perform I-V and C-V measurements and analysis for design verification, process troubleshooting, reliability engineering, and failure analysis. Metrics I/CV software includes support for semiconductor parameter analyzers, C-V meters, low leakage switch matrixes, and semi-automatic probe stations.

### SYSTEM SOFTWARE

Build complete test systems using Metrics I/CV. It is designed to extend the capabilities of existing test and measurement development environments that are used to automate semiconductor characterization measurements on wafer level or packaged devices. The software provides an intuitive platform for developing, editing, and executing complex test plans found in automated lab test systems. Metrics I/CV supports mixed configurations consisting of popular system components from popular test equipment manufacturers:

- Semiconductor parameter analyzers
- CV/LCRZ meters
- Switch matrixes
- Wafer probers with thermal chucks
- Power supplies, pulse generators, etc.  
(with supported development environments)



### WIZARD OPERATOR SHELL

Test wizards provide step-by-step instructions to the operator when entering runtime information, selecting wafer navigation plans, selecting test plans, and starting a test. Test wizards are conveniently organized and launched from toolbars.

### TEST SEQUENCING TOOLS

Test sequencing tools provide access to a library of built-in software components, supporting all the functions necessary to create a variety of test plans at both Module and Die level. The script editor provides a “wizard-based” interface for building a test script so the user does not have to learn complicated command syntax or spend time debugging mistyped commands. Components include:

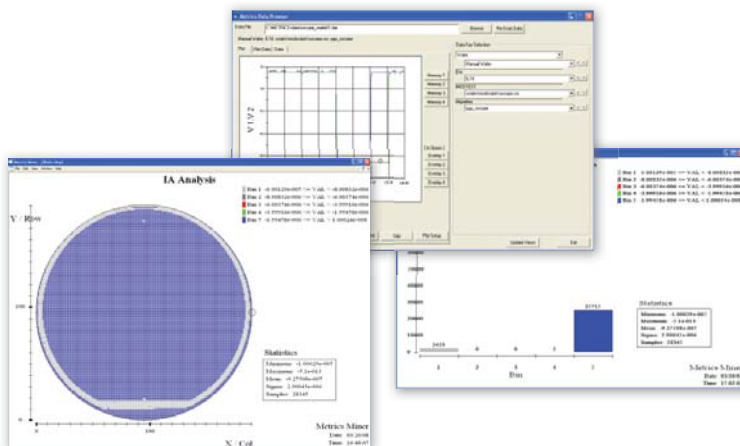
- Automated sub-die prober movement
- Executing a switch connection
- Executing a test algorithm

### AUTO-ANALYSIS AND REPORTING

Data analysis tools included for extracting parametric quantities from the test data and generating several standard reports and graphs, including:

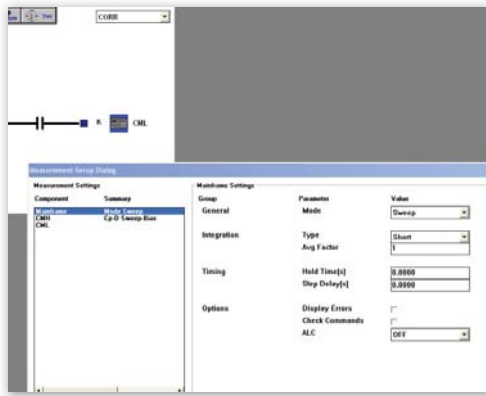
- Color wafer maps
- Histograms
- Parameter statistics
- Parametric values vs. die location
- Tables of I-V or C-V raw data

These tools can also be installed on a second PC to allow the analysis of data without interfering with data collection.



## GRAPHICAL ALGORITHM GENERATION

Tests can be generated and edited using the integrated Metrics ICS graphical workspace editor, which allows rapid test development with no programming required.

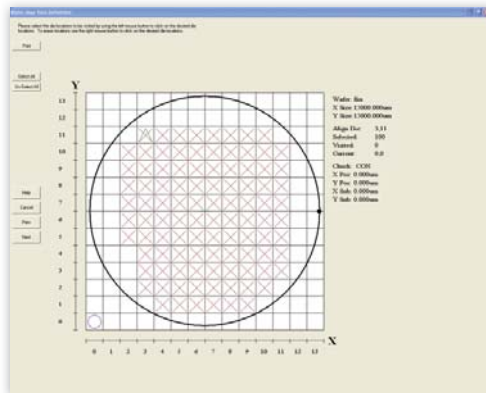


## WAFER PROBE NAVIGATION

Wafer probe navigation control provides support for most popular semi-automatic and automatic probe stations. The user can define probe plans including sub-die movement for performing automated test of multiple modules or individual devices across a wafer.

The new VBScript drivers for vision and thermal control is featured exclusively in our Metrics I/ CV Annual License product. The VBScript drivers provide the following advantages:

- VBScript source code to allow for user modifications.
- Use VBScript source templates to create your own Probe or Thermal Drivers for non-supported equipment.

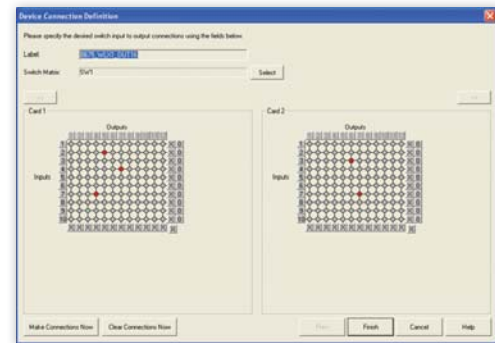


## SWITCH MATRIX CONTROL

The Device Connections Editor now supports an “Import” function which will automatically create device connections including path and subdirectories under the default root folder from information contained in a user specified file.

- Supported switch matrix connections can be populated using external ASCII files.
- Full duplicate setting detection with optional overwrite capability.

Interactive switch matrix control allows the selection of cross-point connections between test instruments and device pins. It automates the execution of multiple connections when using a probe card to make contact to multiple devices on a wafer. Drivers are available for many popular switch matrixes, supporting multiple switch mainframes and a variety of switch matrix and multiplexer cards. Visit our website for a complete list of supported drivers.



## INTEGRATED VBSCRIPT TEST DEVELOPMENT

The new VBScript Development Kit is featured exclusively in our Metrics I/ CV Annual License product. Complex tests can be developed in the Integrated VBScript editor which provides a full-featured script editor with syntax assistance, an interactive test execution environment, and comprehensive debugger.

- New Integrated Development Environment – math functions for performing most parameter extraction tasks and additional decision branch test support.
- New Instrument Control Library Functions – high-level libraries for low-level GPIB access to instrument-specific command strings.
- Open source for advanced test methods including CV, WLR and Non-Volatile Memory characterization.

	Annual License	Perpetual License
License Period	1 year	Does not expire - runs only on supported OS and PC configurations at time of purchase
Support Period	1 year	90 days
Support Type	Phone/Email	Email only
Test Algorithms	ICS Examples NVM Test Algorithms WLR Test Algorithms Parametric Algorithms	ICS Examples Only
Upgrades	All new features as they are added	Fixes Only

**SOFTWARE CUSTOMIZATION & TRAINING** - Provided by quotation (NRE charges apply)

For more information visit our website at [www.metricstech.com](http://www.metricstech.com) or call us at 505-761-9630.